

# SEMI F47 Voltage Sag Immunity Test Report for Power Supply FPS300.241-002-101



# Other devices covered by this report: FPS300.aab-ccc-ddd One-phase input, 300W output

aa: blank	
<b>b:</b> 1	Standard version, adjustable output voltage
2	Standard version, output voltage not adjustable
5	Version with multiple outputs individually current limited
6	Version with multiple NEC CLASS 2 limited power source outputs
7	Version with regular and NEC CLASS 2 limited power source outputs
ccc: 001-999	Defines the connection terminal module
<b>ddd:</b> 001-999	Defines product variant (consecutive number)

# SEMI F47 Test Report



Document Number	FPS300.24b Semi F47 Rev1 DB1	
Approval Order Number	AN447 internal project	
Standards	Sag Immunity Compliance IEC 61000-4-11 2004 +A1 Electromagnetic compat techniques - Voltage dipe	ICONDUCTOR PROCESSING EQUIPMENT - Voltage e Tests
Applicant	PULS GmbH Elektrastraße 6 81925 Munich, Germany	,
Test Laboratory	PULS Vario GmbH Kranichberggasse 6 1120 Vienna, Austria	
Test Engineer	David Baumhackl	
Test Date	21.09.2020	
Description of Test Device	Built-in power supplies for DIN-Rail mounting	
Devices under Evaluation	FPS300.241-002-101 Input: AC 100-240V, Output: DC 24-28V, 300W	
S/N of Devices	FPS300.241-002-101: S/N: 20828210	
Application Details	Input voltage: Input frequency: Output load:	1-Phase AC 100V - 240V 50 or 60Hz 300W



**PASS/FAIL Criterions:** 

Test Result:

#### PASS

value

The test device passed all essential SEMI F47-0706 tests according to the defined application details without any limitations and is qualified to bear the following approval mark:

The output voltage is not allowed to deviated more than 5% of the initial

DC OK contact is not allowed to trigger during and after the test

In accordance with paragraph 7.8.2 a) of SEMI F47-0706



Since DC power supplies, as covered in this test report, are only components of a semiconductor processing equipment, the tests of the SEMI F47 standard were conducted with selected rated characteristics of the DC power supply.

The system integrator of the final semiconductor processing equipment needs to judge if the results of this test report are compatible with the SEMI F47 requirements of his system or if test data under other operating conditions are additionally required.

The system integrator also needs to judge if the results of the inrush current peaks are compatible with the selected external fuses for input protection.

The system integrator also needs to be aware about aging effects. It is expected that the ride through time can be reduced by 15% at end of the specified lifetime expectancy.

A SEMI F47 certificate is not intended for this type of component, however the product fulfils the general requirements and can be marked with the following symbol.

Approved

Harald Etlinger Sr. Qualification Eng. PULS Vario GmbH, Vienna

**Date of Approval** 

24.09.2020



# Copy of marking plate:

FPS300.241.002-101 Power Supply 1-Phase, 24V, 300W Input: AC 100-240V, 4-1.7A, 50-60Hz Output: Continuous: DC 24-28V, 360W (below +45°C) DC 24-28V, 360W (below +45°C) DC 24-28V, 300W (at +55°C) DC 24-28V, 150W (at +70°C)	Installation by professional personnel only <b>WARNING</b> READ FPS300.241-002-101 INSTALLATION MANUAL <b>ATTENTION</b> LIRE LE MANUEL D'INSTALLATION DE FPS300.241-002-101	<u>≷</u> ⊕ <u>∧</u> ∮ € 9)
Up to 60s: DC 24-28V, 600W (below +55°C) DC 24-28V, 300W (at +70°C) Derate linearly between +55°C and +70°C Operational temperature range: -25°C to +70°C	PULS GmbH, Elektrastr. 6, 81925 Munich, Germany www.pulspower.com Designed in Germany, Assembled in the Czech Republic	S/N 20 828 210 ≩

#### List of Test Equipment

Туре	Model	Inventory number
AC Source	Kikusui PCR3000WE2	10372
Scope	LeCroy WS454	10130
Scope	LeCroy WS424	10179
Current Probe	LeCroy CP150	10266
Differential Probe	LeCroy AP031	10262
el. Load	Chroma 63201 - 2.6kW	10053

The test equipment complies with the requirements of IEC 61000-4-11.

The peak current capability of the test generator was evaluated according Annex A of IEC 61000-4-11 and is able to deliver minimum 32.7A.

#### **Test Specification for SEMI F47 compliance**

Voltage Sag Immunity according to the following table:

Sag depth#1	Duration	Duration at 50 Hz	Duration at 60 Hz
50%	200ms	10 cycles	12 cycles
70%	500ms	25 cycles	30 cycles
80%	1000ms	50 cycles	60 cycles

#1 Sag depth is expressed in percent of remaining nominal voltage. For example, during a 70% voltage sag on a 200 volt nominal system, the voltage is reduced during the sag to 140 volts and not 60 volts.



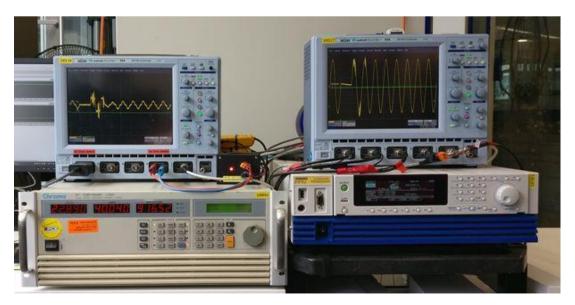
# **Test Setup**

The unit under test in normal operating condition mounted in climate chamber. The input is connected to an AC Source. The input voltage is measured with a 100:1 differential probe and the input current is measured with current probes. These probes are connected to oscilloscopes.

The output is connected to an active load. The output voltage is connected directly to the oscilloscope. "DC-OK" signal is also measured with an oscilloscope.

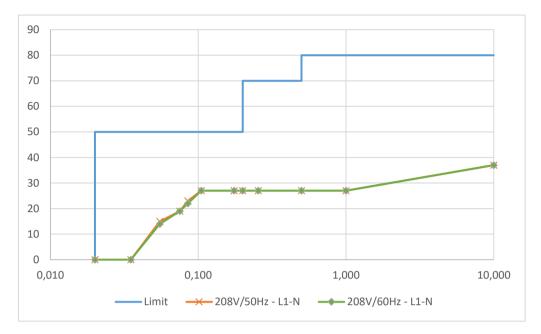
Input and output voltages are measured with oscilloscope #1 and input currents with oscilloscope #2.

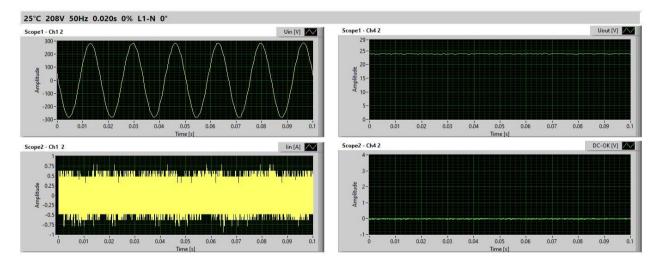


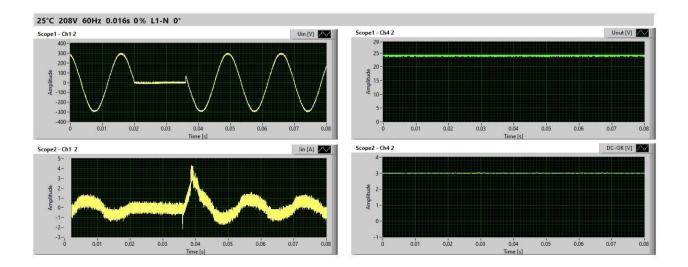




# Voltage Sag Results









# Conducted Tests at 208V 50Hz

Input Voltage	208Vac
Input Frequency	50Hz
Output Voltage	24V
Output Current	12.5A
Ambient Temperature	25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0,020	0	4,4	-1,7
0,200	50	3,8	-2,5
0,500	70	1,9	-1,9
1	80	1,6	-1,7
10	80	1,6	-1,6

#### Informational measurements

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0,020	0	0,175	27
0,035	0	0,200	27
0,055	15	0,255	27
0,075	19	0,500	27
0,085	23	1	27
0,105	27	10	37

# Conducted Tests at 208V 60Hz

Input Voltage	208Vac
Input Frequency	60Hz
Output Voltage	24V
Output Current	12.5A
Ambient Temperature	25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0,016	0	4,4	-2
0,200	50	4,1	-2,3
0,500	70	1,7	-1,7
1	80	1,4	-1,7
10	80	1,6	-1,7

# Informational measurements

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0,016	0	0,175	27
0,035	0	0,200	27
0,055	14	0,255	27
0,075	19	0,500	27
0,085	22	1	27
0,105	27	10	37



#### Inrush current measurements according 61000-4-11 at 208V 50Hz

Input Voltage	208Vac
Input Frequency	50Hz
Output Voltage	24V
Output Current	12.5A
Ambient Temperature	25°C

Peak input current measurements on unit under test:

First two measurements turn off input power for EUT for 5 minutes and then

Measure peak input current when AC turned on at 90°:	4.2A
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Measure peak input current when AC turned on at 270°: 1.4A Next two measurements turn on the input power for EUT for at least 1 minute then turn off input power for 5s and on again.

Measure peak input current when AC turned on at 90°:	3.9A
Measure peak input current when AC turned on at 270°:	4.1A

#### Inrush current measurements according 61000-4-11 at 208V 60Hz

Input Voltage	208Vac
Input Frequency	60Hz
Output Voltage	24V
Output Current	12.5A
Ambient Temperature	25°C

Peak input current measurements on unit under test:

First two measurements turn off input power for EUT for 5 minutes and thenMeasure peak input current when AC turned on at 90°:3.4AMeasure peak input current when AC turned on at 270°:3.9Aon again.4.4AMeasure peak input current when AC turned on at 90°:4.4AMeasure peak input current when AC turned on at 270°:4.1A



#### Operating conditions and their influence in test results:

a) Ambient temperature:

Control measurements show that the ambient temperature has only a minor influence in the ride-through time test results.

Depending on the used topology to reduce the input inrush current, the ambient temperature can have a major influence in the arising peak current after the sag test. Therefore, tests were performed at ambient temperatures of 25°C and +60°C.

It is assumed that semiconductor processing equipment is never used at lower temperatures than +25°C. Although the power supply itself is specified down to -25°C, a test at such low temperatures is not performed.

b) Mains frequency 50Hz vs. 60Hz:

Control measurements show that 50Hz testing is more critical than 60Hz testing. Therefore, unless otherwise noted, all tests were performed with a mains frequency of 50Hz.

c) Output voltage 24V vs. 28V:

The ride-through time depend on the stored energy in the input capacitors and the amount of output power. The output voltage is not essential as long as the output power is constant.

The adjusted output voltage has no influence in input currents peaks after input voltage sags. Therefore, unless otherwise noted, all tests were performed with an output voltage of 24Vdc.



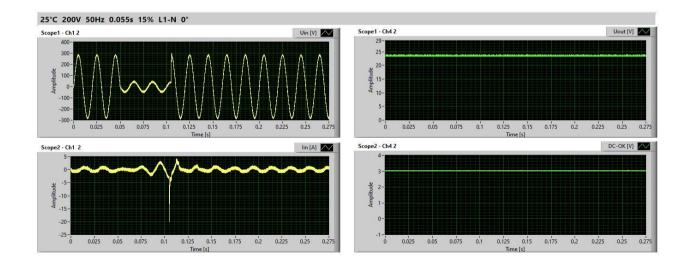
# APPENDIX

# Informational measurements at 200V

200Vac
50Hz
24V
12.5A
25°C

#### Informational measurements

Sag duration	Voltage remaining	Positive peak current	Negative peak current
[s]	[%]	[A]	[A]
0,020	0	4,5	-1,7
0,035	0	4,4	-11,3
0,055	15	4,2	-20
0,075	20	4,7	-18,9
0,085	25	9,2	-3,9
0,105	28	8,6	-3,9
0,175	28	4,2	-8
0,200	28	4,5	-3,6
0,255	28	3,9	-8
0,500	28	4,4	-3,8
1	28	4,2	-3,6
10	38	4,1	-2,5





# Informational measurements at 230V

Input Voltage	230Vac
Input Frequency	50Hz
Output Voltage	24V
Output Current	12.5A
Ambient Temperature	25°C

#### Informational measurements

Sag duration [s]	Voltage remaining [%]	Positive peak current [A]	Negative peak current [A]
0,020	0	0,9	-0,9
0,035	0	3	-20
0,055	14	4,2	-20
0,075	17	4,2	-20
0,085	18	19,8	-4,2
0,105	25	9,1	-4,1
0,175	25	6,1	-9,4
0,200	25	4,2	-4,1
0,255	25	5,6	-9,1
0,500	25	4,1	-4,1
1	25	4,2	-3,8
10	33	3,6	-3

